

Objectives

M Plan Apo FN40 Series Objectives

Widely used in metallographic defect detection, semiconductor chip observation, and material microscopic analysis

- Flat-field apochromatic: "No chromatic aberration, no blurring" across the entire field of view
- Long working distance: Suitable for thick/bulging samples
- Infinite optical path: Strong expandability
- Exclusive for metallography: Adaptable without a cover glass



One Platform Many Possibilities

Contact Us sales@venuslabtech.com

Get a Quote



Get Expert Advice
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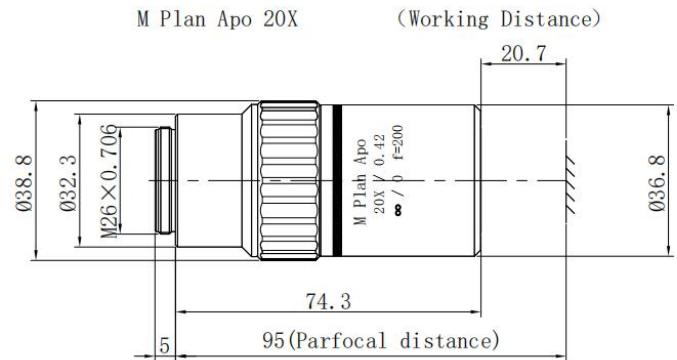
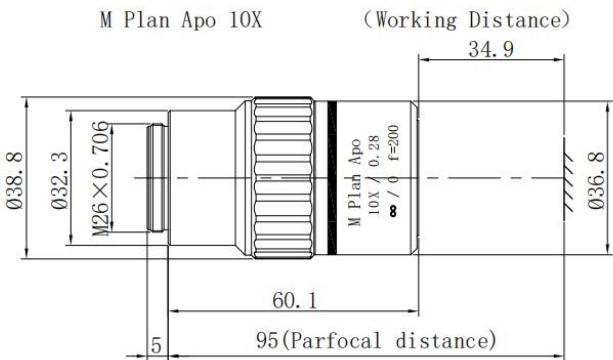
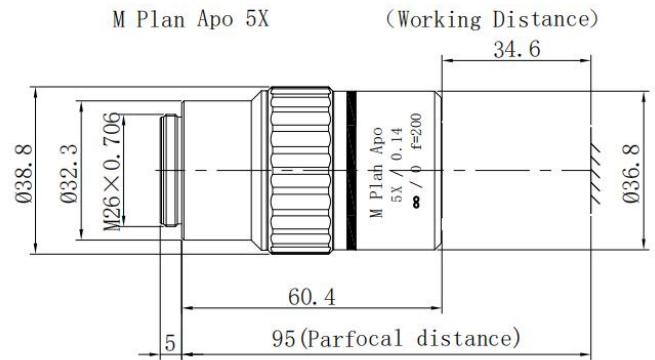
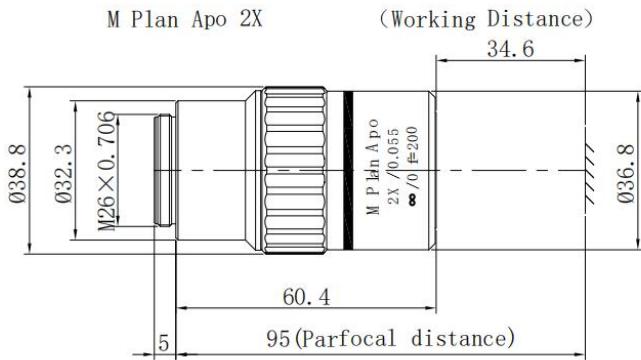


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Overview

Introduction:

- Infinite conjugation, 95mm parfocal distance
- 400-700nm visible spectrum chromatic aberration correction
- FN40mm field of view, flat field correction and clear edges
- Long working distance



Explore Series

Model	NA	±D.F	24 Eyepiece Field of View	WD
VL Plan Apo 2X (FN 40)	0.055	90.9um	20mm	34.6mm
VL Plan Apo 5X (FN 40)	0.14	14.0um	8mm	34.6mm
VL Plan Apo 10X (FN 40)	0.28	3.5um	4mm	34.9mm
VL Plan Apo 20X (FN 40)	0.42	1.6um	2mm	20.7mm

 Get in touch with our team to explore configurations, request a quote, or learn more about customized solutions tailored to your needs.

Let us help you move science forward—faster and smarter.

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